



<b>CCD261-84 SLOWSCAN TEST SHEET</b>	Form No. 10730R Version 2
<b>TITLE: CCD261-84</b>	Sheet 1 of 2

Associated Document:

Device serial number	<b>09312-22-2</b>	Tester (Initials & Clock No.)	<b>JSS 31154</b>
Grade	<b>5</b>	Date	<b>24.08.12</b>
		Device type number	<b>CCD261-84-5-E65</b>

TEST RESULTS

TEST		RESULT	LIMITS			UNITS
			Grade 0	Grade 1	Grade 2	
GAIN (Amplifier responsivity)	OSL	<b>7.22</b>	7.0 min.			$\mu\text{V}/e^-$
	OSR	<b>7.27</b>	7.0 min.			$\mu\text{V}/e^-$
NOISE	OSL	<b>3.1</b>	4.0 max.			rms $e^-$
	OSR	<b>3.2</b>	4.0 max.			rms $e^-$
NON-LINEARITY (to k electrons)	OSL	<b>Fail</b>	0.0 max.			%
	OSR	<b>Pass</b>	0.0 max.			%
CTE (Serial)	OSL	<b>99.999582</b>	99.999 min.			%
	OSR	<b>99.999677</b>	99.999 min.			%
CTE (Parallel)		<b>99.999878</b>	99.999 min.			%
PARALLEL DEFERRED CHARGE			3 max.			-
SERIAL DEFERRED CHARGE			3 max.			-
IMAGE FULL WELL CAPACITY		<b>216.0</b>	150.0 min.			$\text{ke}^-$
REGISTER FULL WELL CAPACITY		<b>204.0</b>	0.0			
DSNU DEFECTS	POINT DEFECTS	<b>4711</b>	500	1000	2000	max.
	COLUMN DEFECTS	<b>169</b>	For Information Only			
PRNU DEFECTS	POINT DEFECTS	<b>5584</b>	For Information Only			max.
	COLUMN DEFECTS	<b>217</b>	For Information Only			
	TRAPS	<b>7</b>	10	20	30	max.
TOTAL SPOTS <sup>1</sup>		<b>10295</b>	1000	2000	4000	
TOTAL COLUMNS <sup>1</sup>		<b>386</b>	4	10	20	max.
MEAN DARK SIGNAL		<b>6.88</b>	0.0 max. at -120°C			$e^-/\text{pix}/\text{hr}$
AREA DARK SIGNAL (32 x 32 block)		<b>47.1</b>	0.0 max. at -120°C			$e^-/\text{pix}/\text{hr}$
TEST		RESULT	LIMITS for device variant			UNITS
			150um basic NIR			
QUANTUM EFFICIENCY at	300 nm	<b>6.7</b>	-			min. %
	350 nm	<b>19.7</b>	-			min. %
	400 nm	<b>56.0</b>	25			min. %
	500 nm	<b>72.2</b>	50			min. %
	650 nm	<b>81.9</b>	75			min. %
	900 nm	<b>78.6</b>	75			min. %
	1000 nm	<b>31.5</b>	30			min. %
PHOTO-RESPONSE NON-UNIFORMITY (1 $\sigma$ ) at	400 nm	<b>3.3</b>	5			max. %
	650 nm	<b>1.8</b>	5			max. %
	900 nm	<b>1.7</b>	5			max. %

Note (1): Minimum separation between adjacent defective columns to be 50 pixels.

Key: n/m = not measured

CUSTOM TESTS (if applicable)




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<b>TITLE: CCD261-84 SLOWSCAN TEST SHEET</b>	Form No. 10730R Version 2
<b>Version: CCD261-84</b>	Sheet 2 of 2

<b>Device serial number</b>	<b>09312-22-2</b>
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OPERATING CONDITIONS

Voltage	Value	Min.	Max.	Units	Voltage	Value	Min.	Max.	Units
VOD	<b>28.0</b>	27	32	V	VSS	<b>10.0</b>	0	10	V
VOG1	<b>3.0</b>	1	3	V	VR $\phi$ (high)	<b>12.0</b>	9	15	V
VRD	<b>17.0</b>	15	19	V	V $\phi$ SW (high)	<b>12.0</b>	9	15	V
VOG2	<b>N/A</b>	VOG1 + 1		V	V $\phi$ R (high)	<b>12.0</b>	9	15	V
VDD	<b>N/A</b>	22	26	V	Vl $\phi$ (high)	<b>10.0</b>	8	14	V

TEST TEMPERATURES

MEASUREMENT	TYPICAL VALUE	ACTUAL VALUE	UNITS
CTE and Deferred charge	-100	<b>-100.0</b>	°C
Others	-85	<b>N/A</b>	°C

NOTES